Spectroscopic Ellipsometer

- J. A. Woollam variable angle spectroscopic ellipsometer (VASE) is located in the Class-1000 cleanroom. It offers spectral wavelength ranges from 193 nm to 2200 nm.
- The system is completely automated with angle of incidence and nondestructive materials analysis.
- Wafers up to a 6" diameter are measurable on this system.

